

FDMA3028N

Dual N-Channel PowerTrench® MOSFET 30 V, 3.8 A, 68 m Ω

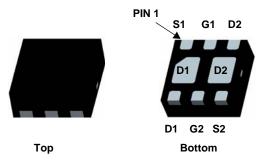
Features

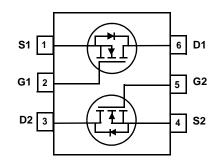
- Max $r_{DS(on)}$ = 68 m Ω at V_{GS} = 4.5 V, I_D = 3.8 A
- Max $r_{DS(on)}$ = 88 m Ω at V_{GS} = 2.5 V, I_D = 3.4 A
- Max $r_{DS(on)} = 123 \text{ m}\Omega$ at $V_{GS} = 1.8 \text{ V}$, $I_D = 2.9 \text{ A}$
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- RoHS Compliant

General Description

This device is designed specifically as a single package solution for dual switching requirements in cellular handset and other ultra-portable applications. It features two independent N-Channel MOSFETs with low on-state resistance for minimum conduction losses. The MicroFET 2x2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.







MicroFET 2x2

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		30	V
V _{GS}	Gate to Source Voltage		±12	V
1	Drain Current -Continuous	(Note 1a)	3.8	^
^I D	-Pulsed		16	A
D	Power Dissipation	(Note 1a)	1.5	W
P_{D}	Power Dissipation	(Note 1b)	0.7	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	
	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	
$R_{ heta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1c)	69	00/14/
	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1d)	151	°C/W
	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1e)	160	
	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1f)	133	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
328	FDMA3028N	MicroFET 2X2	7 "	8 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.6	0.9	1.5	V
$\Delta V_{GS(th)}$ ΔT_J	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-3		mV/°C
	r _{DS(on)} Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 3.8 \text{ A}$		46	68	
_		$V_{GS} = 2.5 \text{ V}, I_D = 3.4 \text{ A}$		56	88	mΩ
¹ DS(on)		$V_{GS} = 1.8 \text{ V}, I_D = 2.9 \text{ A}$		80	123	11152
		$V_{GS} = 4.5 \text{ V}, I_D = 3.8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		72	108	
9 _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 3.8 A		15		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45 V V 0 V	282	375	pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	40	55	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	29	45	pF
R_g	Gate Resistance		2.4		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		5.3	11	ns
t _r	Rise Time	V _{DD} = 15 V, I _D = 3.8 A,	3	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$	15	27	ns
t _f	Fall Time		2.5	10	ns
$Q_{g(TOT)}$	Total Gate Charge	V 45 V L 20 A	3.7	5.2	nC
Q _{gs}	Gate to Source Charge	$V_{DD} = 15 \text{ V}, I_{D} = 3.8 \text{ A}$ $V_{GS} = 5 \text{ V}$	0.4		nC
Q_{gd}	Gate to Drain "Miller" Charge	vGS = 0 v	1		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.3 \text{ A}$	(Note 2)	0.7	1.2	V
t _{rr}	Reverse Recovery Time	I _E = 3.8 A, di/dt = 100 A/μs		12	22	ns
Q _{rr}	Reverse Recovery Charge	$I_F = 3.8 \text{ A}, \text{ di/dt} = 100 \text{ A/} \mu \text{S}$		3.3	10	nC

Electrical Characteristics T_J = 25 °C unless otherwise noted

Notes:

- 1. R_{0JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.

 (a) $R_{\theta JA} = 86 \text{ °C/W}$ when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For single operation.

 - (b) $R_{\theta JA}$ = 173 °C/W when mounted on a minimum pad of 2 oz copper. For single operation.
 - (c) $R_{\theta JA} = 69$ °C/W when mounted on a 1 in² pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB. For dual operation.
 - (d) $R_{\theta JA}$ = 151 °C/W when mounted on a minimum pad of 2 oz copper. For dual operation.
 - (e) $R_{\theta JA} = 160$ °C/W when mounted on a 30mm² pad of 2 oz copper. For single operation.
 - (f) $R_{\rm 0JA}$ = 133 °C/W when mounted on a 30mm² pad of 2 oz copper. For dual operation.



a. 86 °C/W when mounted on a 1 in² pad of 2 oz copper



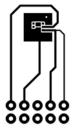
b. 173 °C/W when mounted on a minimum pad of 2 oz copper



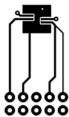
c. 69 °C/W when mounted on a 1 in2 pad of 2 oz copper



d. 151 °C/W when mounted on a minimum pad of 2 oz copper



e. 160 °C/W when mounted on 30mm² pad of 2 oz copper



f. 133 °C/W when mounted on 30mm² of 2 oz copper

2. Pulse Test : Pulse Width < 300 us, Duty Cycle < 2.0%

Typical Characteristics T_J = 25°C unless otherwise noted

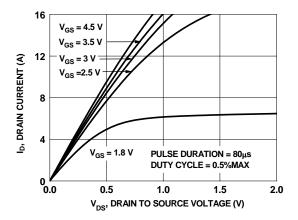


Figure 1. On Region Characteristics

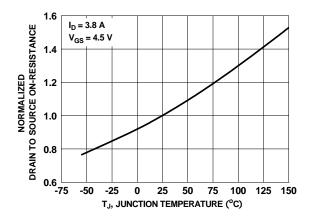


Figure 3. Normalized On Resistance vs Junction Temperature

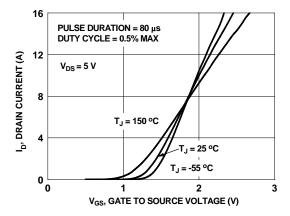


Figure 5. Transfer Characteristics

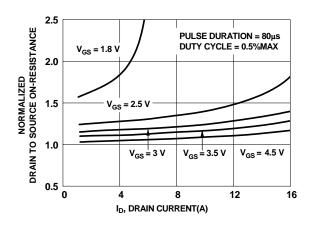


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

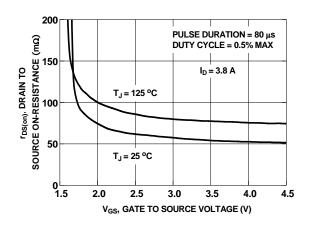


Figure 4. On-Resistance vs Gate to Source Voltage

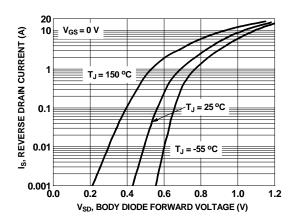


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

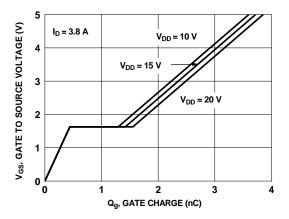


Figure 7. Gate Charge Characteristics

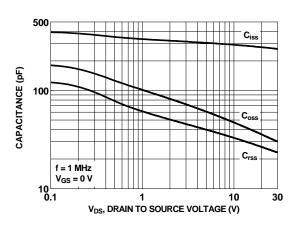


Figure 8. Capacitance vs Drain to Source Voltage

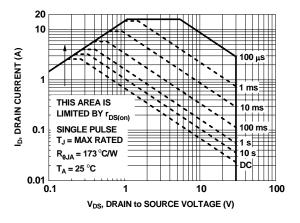


Figure 9. Forward Bias Safe Operating Area

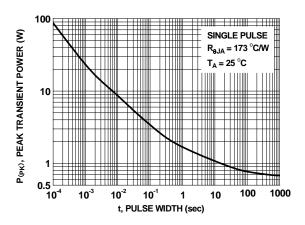


Figure 10. Single Pulse Maximum Power Dissipation

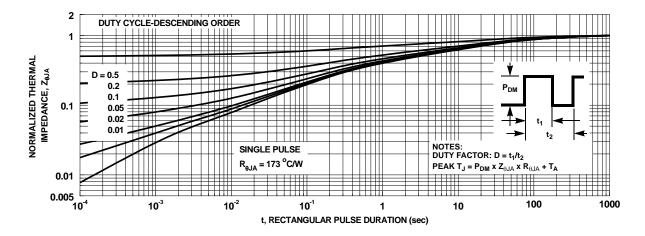
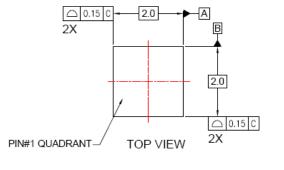
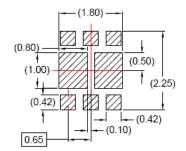


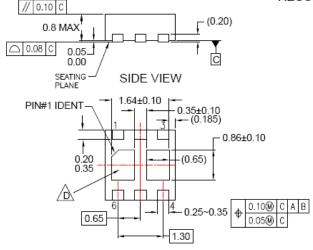
Figure 11. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER

ASME Y14.5M, 1994

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Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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